



# CERTIFICATE

## N°CC0092-20140508

### Applicant

#### TOPSUN

B-101,GIDC,Electronic Estate,Sec-25  
Gandhinagar - 382028 Gujarat - INDIA

### Module type

TEL72PXXX ; XXX=260 to 320W each step of 5W  
TEL60PXXX ; XXX=215 to 265W each step of 5W  
TEL54PXXX ; XXX=200 to 240W each step of 5W  
TEL48PXXX ; XXX=160 to 200W each step of 5W

### Factory

#### TOPSUN

R S No. 892, Near 66KV GEB substation  
Jagudan Cross Road, At & PO-Linch, Ta & Dist- Mehsana  
384435 Gujarat - INDIA

### Test report: 20140508-001 (BOM 1), 20140508-001 (BOM 2)

In consideration of the test results in the above mentioned report, no potential-induced degradation of the tested modules samples have been detected : no degradation of the power output and no default added on EL images.

### References

- IEC TS **62804-1 : 2015**  
Photovoltaic (PV) modules - Test methods for the detection of potential-induced degradation – Part 1: Crystalline silicon

### Conditions

Test method (a) of IEC TS 62804-1 : Module temperature : 60°C ; Chamber relative humidity : 85% ; Test duration : 96h ; Voltage module rated system : 1000V  
Only one polarity tested : Connection (negative bias – Positively grounded) – Only one sample tested on each BOM.  
Each modification of design, material or component is not covered by this type approval. Each modification requires evaluation by a qualifying test laboratory.  
This certificate is only valid for the samples tested and for the tests described in the report mentioned above. It does not imply that a control or supervision of the production process have been done by CERTISOLIS

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Jérôme BECCA VIN, CEO

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